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University of California, Riverside, Department of
Electrical & Computer Engineering, Riverside,
United States

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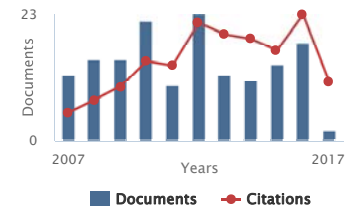
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